Sandrine Bernardini

List of Publications by Year in Descending Order

43 papers	511 citations	12 h-index	21 g-index
46 ext. papers	590 ext. citations	3.8 avg, IF	3.45 L-index

#	Paper	IF	Citations
43	BTEX gas sensor based on hematite microrhombuses. *Sensors and Actuators B: Chemical*, **2021**, 326, 128817	8.7	6
42	Ammonia sensing properties of ZnO nanoparticles on flexible substrate. *International Journal on Smart Sensing and Intelligent Systems*, **2020**, 7, 1-4	0.4	1
41	Light-induced high-spin state in ZnO nanoparticles. *Nanotechnology*, **2020**, 31, 095707	3.4	2
40	Trends in metal oxide thin films: Synthesis and applications of tin oxide **2020**, 219-246		3
39	Highly selective ozone gas sensor based on nanocrystalline Zn0.95Co0.05O thin film obtained via spray pyrolysis technique. *Applied Surface Science*, **2019**, 478, 347-354	6.7	28
38	One-Dimensional V2O5/TiO2 Heterostructures for Chemiresistive Ozone Sensors. *ACS Applied Nano Materials*, **2019**, 2, 4756-4764	5.6	28
37	Efficiency of new ozone filters for NO2 sensing and air depollution. *Sensors and Actuators B: Chemical*, **2018**, 265, 591-599	8.5	7
36	Ammonia Detection at Low Temperature by Tungsten Oxide Nanowires. *Proceedings (mdpi)*, **2018**, 2, 983	0.3	1
35	Silver Growth on Tungsten Oxide Nanowires for Nitrogen Dioxide Sensing at Low Temperature. *Proceedings (mdpi)*, **2018**, 2, 946	0.3	
34	UV-enhanced ozone gas sensing response of ZnO-SnO2 heterojunctions at room temperature. *Sensors and Actuators B: Chemical*, **2017**, 240, 573-579	8.5	80
33	Selective Detection of NO2 with Specific Filters for O3 Trapping. *Proceedings (mdpi)*, **2017**, 1, 405	0.3	1
32	ZnO/SnO2 Heterojunctions Sensors with UV-Enhanced Gas-Sensing Properties at Room Temperature. *Proceedings (mdpi)*, **2017**, 1, 418	0.3	4
31	Ozone Sensors Working at Room Temperature Using Zinc Oxide Nanocrystals Annealed at Low Temperature. *Proceedings (mdpi)*, **2017**, 1, 423	0.3	3
30	Te implantation in Ge(001) for n-type doping applications. *Materials Science in Semiconductor Processing*, **2016**, 42, 215-218	4.3	1
29	Local Structure and Surface Properties of CoZnO Thin Films for Ozone Gas Sensing. *ACS Applied Materials & Interfaces*, **2016**, 8, 26066-26072	9.5	45
28	Formation of germanium oxide microcrystals on the surface of Te-implanted Ge. *Nuclear Instruments & Methods in Physics Research B*, **2015**, 365, 252-255	1.2	
27	Ozone and nitrogen dioxide gas sensor based on a nanostructured SrTi0.85Fe0.15O3 thin film. *Journal of Alloys and Compounds*, **2015**, 638, 374-379	5.7	37

26	Nanoporous Ge thin film production combining Ge sputtering and dopant implantation. *Beilstein Journal of Nanotechnology*, **2015**, 6, 336-42	3	4
25	An easy method of preparing ozone gas sensors based on ZnO nanorods. *RSC Advances*, **2015**, 5, 19528-19533	3.7	58
24	Ozone flexible sensors fabricated by photolithography and laser ablation processes based on ZnO nanoparticles. *Sensors and Actuators B: Chemical*, **2014**, 203, 602-611	8.5	50
23	Ammonia detection by a novel Pyrex microsystem based on thermal creep phenomenon. *Sensors and Actuators B: Chemical*, **2014**, 192, 714-719	8.5	7
22	Ozone Sensor on Flexible Substrate by ZnO Nanoparticles. *Key Engineering Materials*, **2014**, 605, 163-166	0.4	3
21	Direct Laser Patterning of a Gas Sensor on Flexible Substrate. *Procedia Engineering*, **2014**, 87, 899-902		2
20	Microfluidic gas sensor with integrated pumping system. *Sensors and Actuators B: Chemical*, **2012**, 170, 45-50	8.5	13
19	A New Active Organic Component for Flexible Ammonia Gas Sensors. *Procedia Engineering*, **2011**, 25, 1069-1072		3
18	Fabrication and characterization of gas detection microfluidic system. *Procedia Engineering*, **2010**, 5, 1188-1191	2	
17	All solution processed flexible ammonia gas and light sensors based on □hexyl-distyrylbithiophene films. *Sensors and Actuators B: Chemical*, **2010**, 151, 77-82	8.5	14
16	Energy state distributions of the Pb centers at the (100), (110), and (111) Si□SiO2 interfaces investigated by Laplace deep level transient spectroscopy. *Applied Physics Letters*, **2008**, 92, 242104	3.4	23
15	Reliability degradation of thin HfO2/SiO2 gate stacks by remote RF hydrogen and deuterium plasma treatment. *Thin Solid Films*, **2008**, 517, 207-208	2.2	7
14	Nanoscale electrical characterization of ultrathin high-k dielectric MOS stacks: A conducting AFM study. *Materials Science in Semiconductor Processing*, **2008**, 11, 250-253	4.3	3
13	Chemical and optical profiling of ultra thin high-k dielectrics on silicon. *Thin Solid Films*, **2008**, 517, 459-461	2.2	3
12	Electrically active defects induced by hydrogen and helium implantations in Ge. *Materials Science in Semiconductor Processing*, **2008**, 11, 354-359	4.3	4
11	Extrinsic stacking fault generation related to high□ dielectric growth on a Si substrate. *Microelectronic Engineering*, **2007**, 84, 2374-2377	2.5	
10	Nanoscale imaging and X-ray spectroscopy of electrically active defects in ultra thin dielectrics on silicon. *Microelectronic Engineering*, **2007**, 84, 2286-2289	2.5	
9	Reliability nano-characterization of thin SiO2 and HfSixOy/SiO2 gate stacks. *Microelectronic Engineering*, **2007**, 84, 2290-2293	2.5	12

8	The impact of negative-bias-temperature-instability on the carrier generation lifetime of metal-oxynitride-silicon capacitors. *Journal of Applied Physics*, **2006**, 100, 124103	2.5	21
7	. *IEEE Nanotechnology Magazine*, **2005**, 4, 360-368	2.6	19
6	Effect of fixed dielectric charges on tunnelling transparency in MIM and MIS structures. *Microelectronic Engineering*, **2004**, 72, 90-95	2.5	1
5	DC and AC MOS transistor modelling in presence of high gate leakage and experimental validation. *Solid-State Electronics*, **2004**, 48, 597-608	1.7	2
4	Origin and repartition of the oxide fixed charges generated by electrical stress in memory tunnel oxide. *Applied Physics Letters*, **2004**, 84, 4251-4253	3.4	1
3	Study of trap centres in silicon nanocrystal memories. *Materials Science and Engineering B: Solid-State Materials for Advanced Technology*, **2003**, 102, 99-107	3.1	6
2	A new floating gate compact model applied to flash memory cell. *Journal of Non-Crystalline Solids*, **2003**, 322, 250-255	3.9	5
1	A tunneling model for gate oxide failure in deep sub-micron technology		1